

Annex B: Measurement Results
Tested Model :KB1001
Report Number: WSCT-ANAB-R&E250900072A-SAR

Measurement Report for Device, BACK, 2.4 GHz, Channel 11 (2462.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	2.4 GHz	-	2462.000, 11	7.07	1.81	41.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

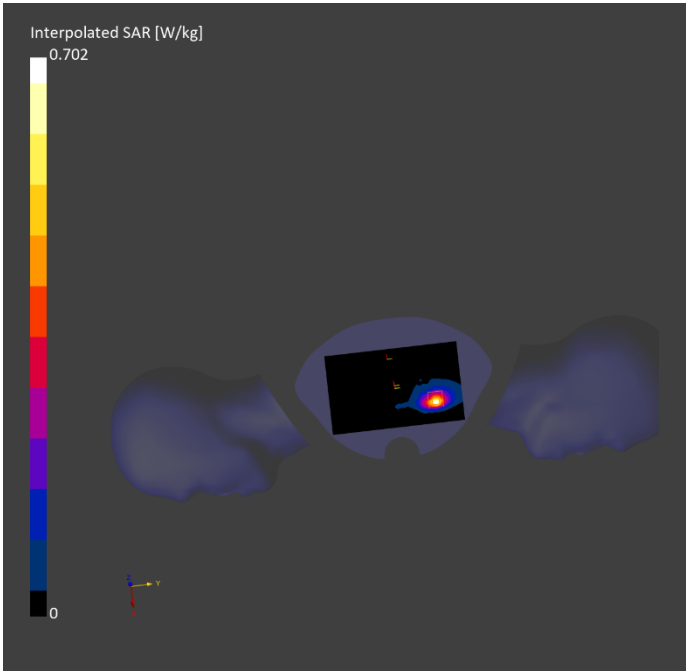
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-10	2025-10-10
psSAR1g [W/kg]	0.496	0.491
psSAR10g [W/kg]	0.219	0.211
Power Drift [dB]	-0.03	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.1
Dist 3dB Peak [mm]		5.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 1 / 2A, Channel 36 (5240.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 1 / 2A		5240.000, 48	5.5	4.51	36.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

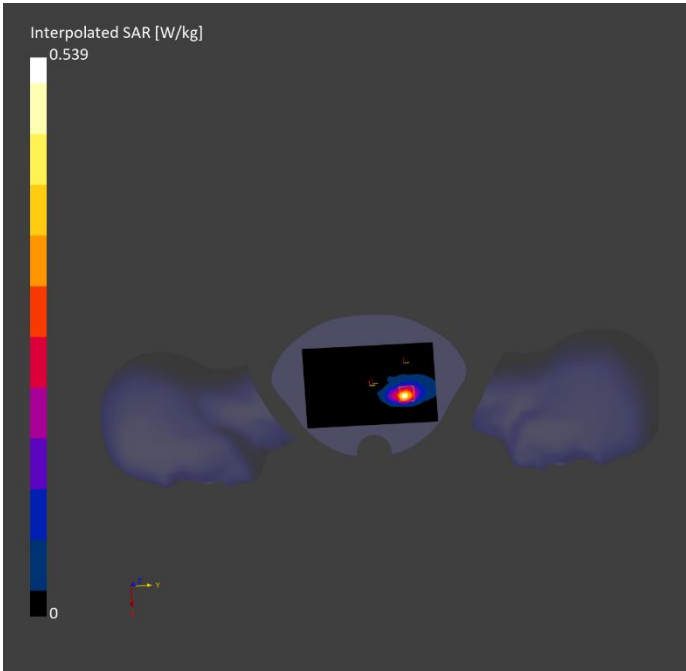
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-13	2025-10-13
psSAR1g [W/kg]	0.355	0.381
psSAR10g [W/kg]	0.124	0.164
Power Drift [dB]	0.06	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.1
Dist 3dB Peak [mm]		6.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 1 / 2A, Channel 52 (5260.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 1 / 2A		5260.000, 52	5.27	4.68	36.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

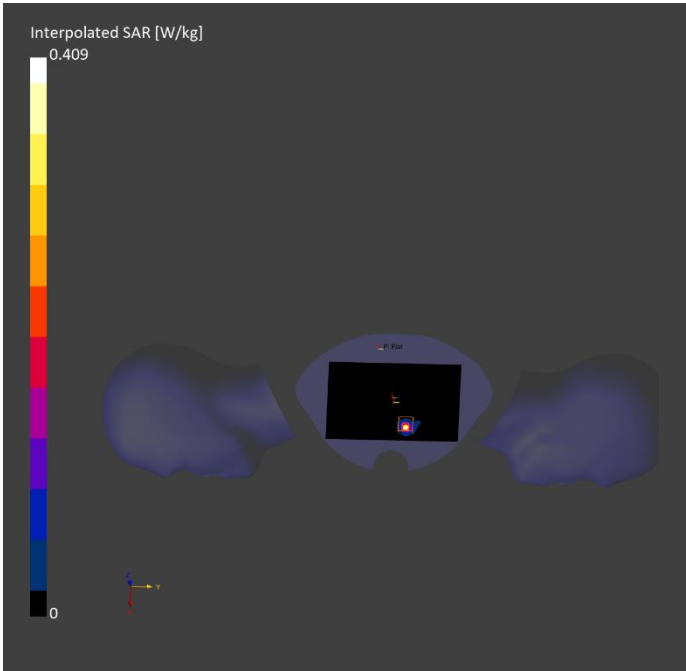
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.2
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-13	2025-10-13
psSAR1g [W/kg]	0.218	0.306
psSAR10g [W/kg]	0.052	0.061
Power Drift [dB]	-0.13	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.1
Dist 3dB Peak [mm]		3.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 2C, Channel 116 (5580.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 2C		5580.000, 116	4.93	4.98	35.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

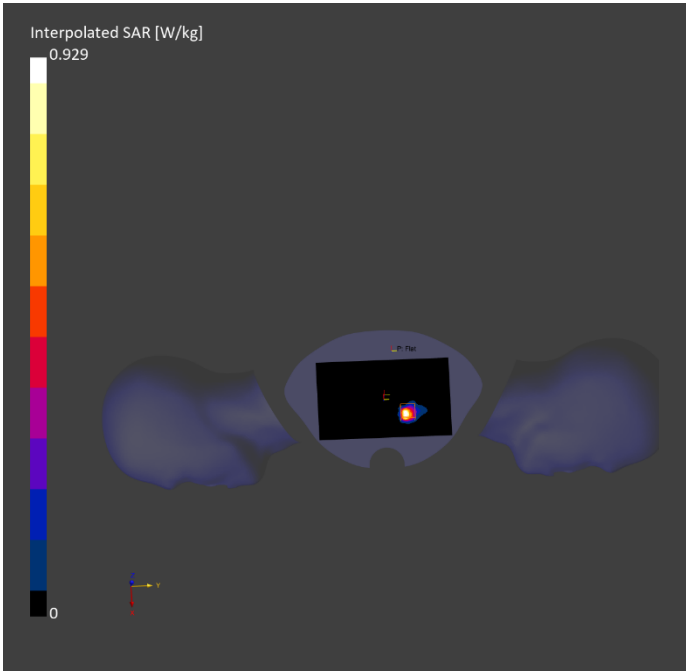
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.2
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-20	2025-10-20
psSAR1g [W/kg]	0.670	1.20
psSAR10g [W/kg]	0.201	0.253
Power Drift [dB]	0.22	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.1
Dist 3dB Peak [mm]		3.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 2C, Channel 122 (5610.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 2C		5610.000, 122	4.93	5.01	35.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

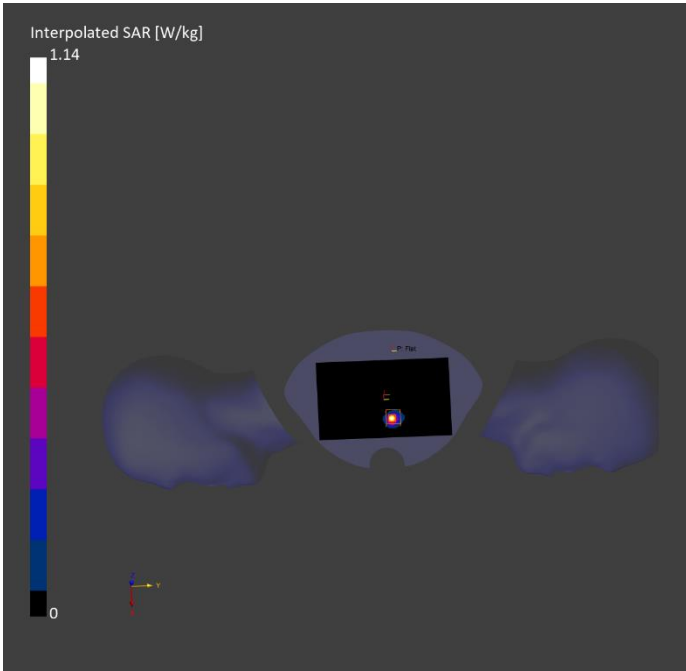
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.2
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-20	2025-10-20
psSAR1g [W/kg]	0.645	0.769
psSAR10g [W/kg]	0.160	0.156
Power Drift [dB]	1.44	1.88
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.0
Dist 3dB Peak [mm]		3.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 2C, Channel 140 (5700.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 2C		5700.000, 140	4.93	5.11	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

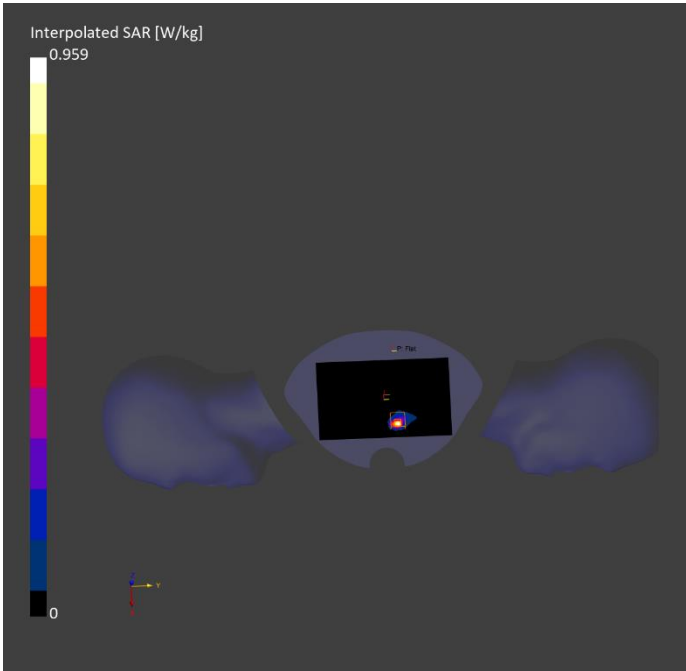
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.2
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-20	2025-10-20
psSAR1g [W/kg]	0.557	1.03
psSAR10g [W/kg]	0.142	0.211
Power Drift [dB]	1.90	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.5
Dist 3dB Peak [mm]		3.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 3, Channel 149 (5745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 3		5745.000, 149	4.87	5.17	35.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

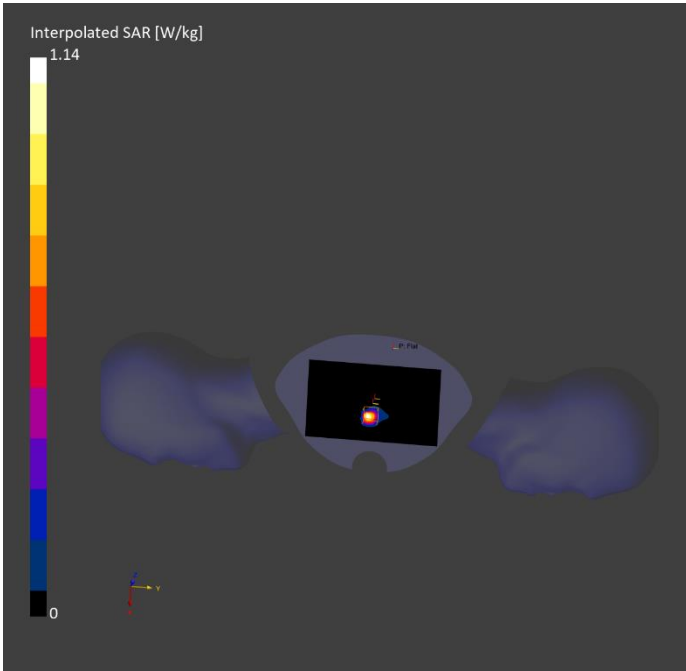
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-21	2025-10-21
psSAR1g [W/kg]	0.784	1.32
psSAR10g [W/kg]	0.233	0.273
Power Drift [dB]	1.09	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.9
Dist 3dB Peak [mm]		4.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 3, Channel 157 (5785.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 3		5785.000, 157	4.87	5.21	35.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

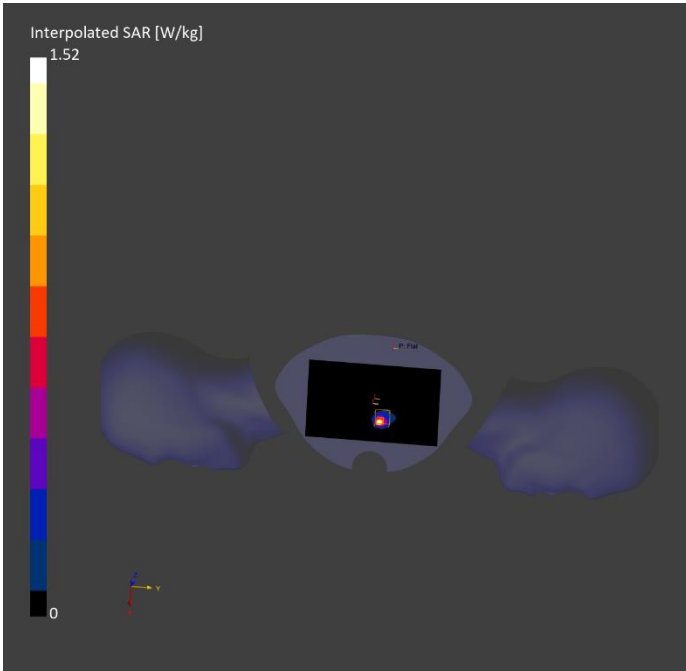
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-21	2025-10-21
psSAR1g [W/kg]	0.856	1.24
psSAR10g [W/kg]	0.217	0.260
Power Drift [dB]	0.32	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		49.3
Dist 3dB Peak [mm]		4.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, U-NII 3, Channel 165 (5825.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	U-NII 3		5825.000, 165	4.87	5.26	35.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2216	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

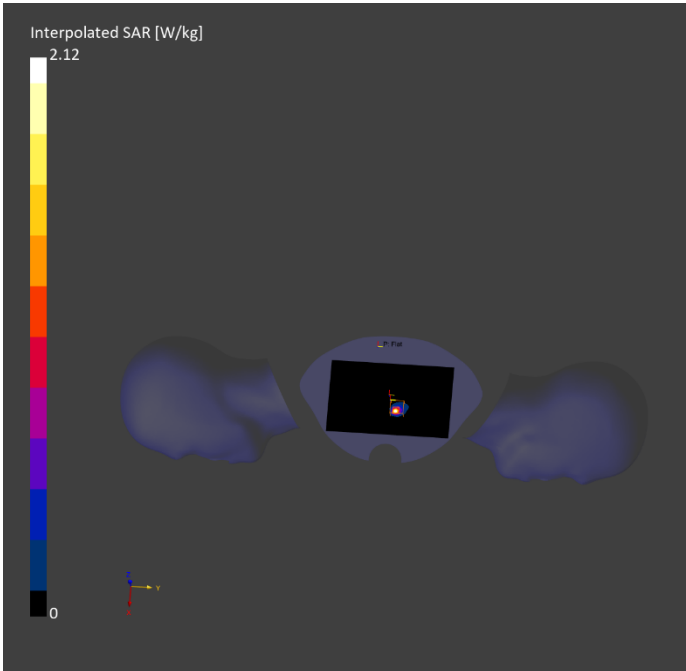
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-21	2025-10-21
psSAR1g [W/kg]	1.10	1.20
psSAR10g [W/kg]	0.250	0.250
Power Drift [dB]	0.01	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		55.7
Dist 3dB Peak [mm]		3.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, ISM 2.4 GHz Band, Channel 39 (2441.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HBBL 5-10000MHz	BACK, 0.00	ISM 2.4 GHz Band		2441.000, 39	7.9	1.82	40.27

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz , --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-10-10	2025-10-10
psSAR1g [W/kg]	0.035	0.034
psSAR10g [W/kg]	0.021	0.019
Power Drift [dB]	-0.14	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.3
Dist 3dB Peak [mm]		6.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

